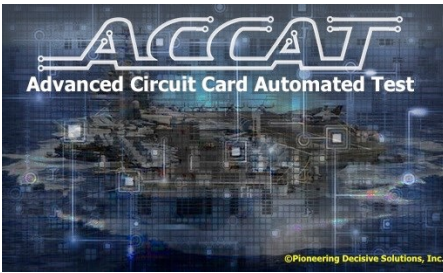


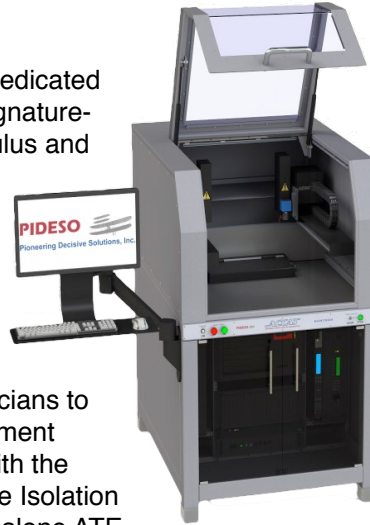
# ADVANCED CIRCUIT CARD AUTOMATED TEST



High-cost, high-demand circuit cards are key targets for cost avoidance and readiness improvements for DoD weapons systems. The ACCAT is a new concept in automated circuit card testing combining parametric test, proven Huntron Analog Signal Analysis, and GUI-based Parallel Test (SimulTest®).

The system is dedicated to providing the best attributes of Automated Test with signature-based diagnostics augmentation. ACCAT provides stimulus and measurement capabilities necessary for full functional / parametric testing of circuit card assemblies. The system is capable of supporting test and repair in all DoD depot support facilities and at commercial rework centers.

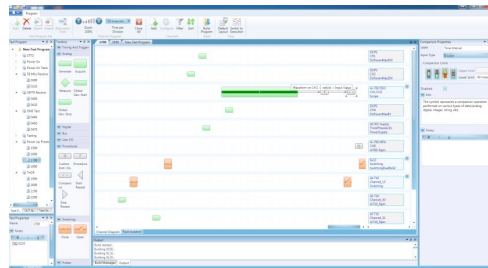
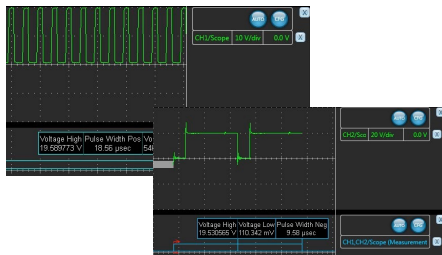
SimulTest®'s drag-n-drop graphical development environment enables engineers as well as trained technicians to easily create simple or complex test programs. Development time is reduced as well as development costs. ACCAT with the SimulTest® coherent graphical results display and Failure Isolation Matrix make diagnostics more powerful than either standalone ATE or Probing Systems.



**Supported Instruments can be mixed & matched to meet test requirements:**

Power Supplies	Keysight
AC Power Supplies	Ametek
DC Power Supplies	Ametek
Digital I/O	MTS
Switching	MTS
MUX	MTS
Digitizers	MTS
Multimeters	MTS
DMMs	National
AWGs	National
Digitizers	National
Power Supplies	National
Di50	Teradyne
Bi50	Teradyne
Ai710	Teradyne
Ai760/2	Teradyne

*\* All IVI base class instruments regardless of manufacturer.  
\*\* New common instruments at no added cost.*



ACCAT uses low cost, high fidelity Virginia Panel S6 mass interconnect and adaptors to interface with the Test Program Set (TPS). The S6 interface supports low cost high fidelity interface devices and simplify TPS hardware design.



## ACCAT “focused on meeting the demands of circuit card test and repair.”

- Intuitive TPS Development Suite
- Low-Cost ITAs & IDs
- Matrix Interface
- Automated Transition to Probing
- Straightforward Fault Isolation Matrix
- Huntron’s Analog Signal Analysis
- Graphical Results for Selected Tests
- Coherent / Parallel Testing
- Short TPS Time-To-Market
- Shorter Run Times
- Configurable to Test Requirements

